Index of Claims 10776789 Examiner Pan, Yuwen Application/Control No. Applicant(s)/Patent Under Reexamination BEDNASZ ET AL. Art Unit 2618

✓	Rejected	-	Cancelled	N	Non-Elected	Α	Appeal
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☐ Claims renumbered in the same order as presented by applicant							□ СРА	□ т.с	□ T.D. □	
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	35	✓	=							
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	Examiner	Art Unit
	Pan, Yuwen	2618

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U.S. Patent and Trademark Office Part of Paper No.: 20080720